

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application: N. HASEGAWA et al
Serial No. 10/096,599
Filed: March 14, 2002

Group Art Unit: 1756
Examiner: S. Rosasco
For: PHOTOMASK AND PATTERN FORMING METHOD
EMPLOYING THE SAME

INFORMATION DISCLOSURE STATEMENT (IDS)
UNDER § 1.97 AND § 1.98

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450


February 13, 2004

Sir:

In accordance with the duty of disclosure, the Applicants inform the Examiner of the documents cited during prosecution of the parent application, USSN 10/096,599.

The Applicants request the Examiner to initial and return a copy of the attached PTO-1449 form as an indication that the references have been considered.

Respectfully submitted,


Daniel J. Stanger
Registration No. 32,846
Attorney for Applicant(s)

MATTINGLY, STANGER & MALUR, P.C.
1800 Diagonal Road, Suite 370
Alexandria, Virginia 22314
Telephone: (703) 684-1120
Facsimile: (703) 684-1157
Date: February 13, 2004

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| FORM PTO-1449 (REV. 7-80) | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. ASA-481-10 | | SERIAL NO. | |
| LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i> | | | | APPLICANT N. HASEGAWA et al | | | |
| | | | | FILING DATE 02/13/04 | | GROUP 1756 | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| * EXAMINER INITIAL | DOCUMENT | DATE | NAME | CLASS | SUBCLASS | FILING DATE <i>(If Appropriate)</i> | |
| | AA | 5,429,897 | 07/04/95 | Yoshioka et al | | | |
| | AB | 5,589,305 | 12/31/96 | Tomofuji et al | | | |
| | AC | 5,472,813 | 12/1995 | Nakagawa et al | | | |
| | AD | 5,574,492 | 11/1996 | Suzuki | | | |
| | AE | 4,360,586 | 11/23/82 | Flanders et al | | | |
| | AF | 4,890,309 | 12/26/89 | Smith et al | | | |
| | AG | 5,328,807 | 07/12/94 | Tanaka et al | | | |
| | AH | 5,364,716 | 11/15/94 | Nakagawa et al | | | |
| | AI | 5,837,405 | 11/17/98 | Tomofuji et al | | | |
| | AJ | 5,660,956 | 08/26/97 | Tomofuji et al | | | |
| | AK | 5,595,844 | 01/21/97 | Tomofuji et al | | | |
| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | DOCUMENT | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES NO | |
| | AL | 62-50811 | 10/27/87 | Japan | | <input type="checkbox"/> | <input type="checkbox"/> |
| | AM | 4-136854 | 05/11/92 | Japan | | <input type="checkbox"/> | <input type="checkbox"/> |
| | AN | 144453 | 06/19/91 | Japan | | <input type="checkbox"/> | <input type="checkbox"/> |
| | AO | 269532 | 12/02/91 | Japan | | <input type="checkbox"/> | <input type="checkbox"/> |
| | AP | 1750/95 | 02/28/95 | Korea | | <input type="checkbox"/> | <input type="checkbox"/> |
| OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, etc.)</i> | | | | | | | |
| | AR | Flanders et al, "Spatial period division - A new technique for exposing submicrometer-line width periodic and quasiperiodic patterns", JOURNAL OF VACUUM SCIENCE TECHNOLOGY, 16(6), Nov/Dec 1979, pp. 1949-1952 | | | | | |
| | AS | | | | | | |
| | AT | | | | | | |
| EXAMINER | | | | DATE CONSIDERED | | | |
| <small>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small> | | | | | | | |

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| U.S. PATENT DOCUMENTS | | | | | | | |
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| | AA | | | | | | |
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| FOREIGN PATENT DOCUMENTS | | | | | | | |
| | DOCUMENT | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES NO | |
| AL | 4-223464 | 08/13/92 | Japan | | | <input type="checkbox"/> | <input type="checkbox"/> |
| AM | 4-204653 | 07/27/92 | Japan | | | <input type="checkbox"/> | <input type="checkbox"/> |
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| AO | | | | | | <input type="checkbox"/> | <input type="checkbox"/> |
| AP | | | | | | <input type="checkbox"/> | <input type="checkbox"/> |
| OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, etc.)</i> | | | | | | | |
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